



# VIS30940

## 30V N-Channel SGT MOSFET

### General Description

- SGT MOSFET Technology
- Low  $R_{DS(ON)}$  at 4.5V  $V_{GS}$
- Low Gate Charge
- High Current Capability
- RoHS and Halogen-Free Compliant

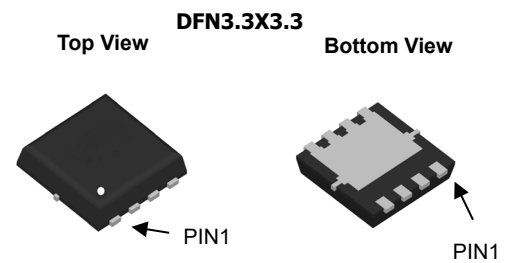
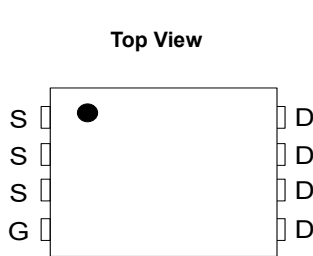
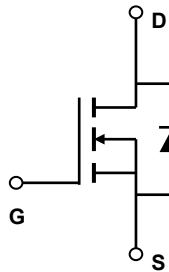
### Applications

- General DC/DC Converters
- VRM Vcore for Notebook and Server
- Load Switch and Battery Power Management
- Motor Drive Bridge Switch

### Product Summary

$V_{DS}$		30V
$I_D$	(at $V_{GS}=10V$ )	32A
$R_{DS(ON)}$	(at $V_{GS}=10V$ , typ)	4.6m $\Omega$
$R_{DS(ON)}$	(at $V_{GS}=4.5V$ , typ)	5.8m $\Omega$

100% UIS Tested  
100%  $R_g$  Tested



Orderable Part Number	Package Type	Form	Minimum Order Quantity
VIS30940	DFN3.3x3.3	Tape & Reel	5000

### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>(5)</sup>	$I_D$	$T_C=25^\circ C$	32
		$T_C=100^\circ C$	32
Pulsed Drain Current <sup>(3)</sup>	$I_{DM}$	150	A
Continuous Drain Current	$I_{DSM}$	$T_A=25^\circ C$	20
		$T_A=100^\circ C$	12.5
Avalanche Current <sup>(3)</sup>	$I_{AS}$	33	A
Avalanche Energy $L=0.1mH$ <sup>(3)</sup>	$E_{AS}$	54	mJ
Power Dissipation <sup>(2)</sup>	$P_D$	$T_C=25^\circ C$	26
		$T_C=100^\circ C$	10.4
Power Dissipation <sup>(1)</sup>	$P_{DSM}$	$T_A=25^\circ C$	3.1
		$T_A=100^\circ C$	1.25
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	$^\circ C$

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>(1)</sup>	$R_{\theta JA}$	30	40	$^\circ C/W$
Maximum Junction-to-Ambient <sup>(1,4)</sup>		Steady-State	60	75
Maximum Junction-to-Case	$R_{\theta JC}$	4	4.8	$^\circ C/W$



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### Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V T <sub>J</sub> =55°C			1 5	μA
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V			±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1.4	1.7	2.3	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =20A T <sub>J</sub> =125° V <sub>GS</sub> =4.5V, I <sub>D</sub> =20A		4.6 6.5 5.8	5.5 7.5	mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =20A		83		S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V		0.72		V
I <sub>S</sub>	Maximum Body-Diode Continuous Current				34	A
<b>DYNAMIC PARAMETERS</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =15V, f=1MHz		1575		pF
C <sub>oss</sub>	Output Capacitance			450		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			35		pF
R <sub>g</sub>	Gate resistance	f=1MHz		2.5		Ω
<b>SWITCHING PARAMETERS</b>						
Q <sub>g</sub> (10V)	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, I <sub>D</sub> =20A		23.2		nC
Q <sub>g</sub> (4.5V)	Total Gate Charge			10.9		nC
Q <sub>gs</sub>	Gate Source Charge			6.9		nC
Q <sub>gd</sub>	Gate Drain Charge			1.5		nC
t <sub>D(on)</sub>	Turn-On Delay Time	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, R <sub>L</sub> =0.75Ω, R <sub>GEN</sub> =3Ω		8		ns
t <sub>r</sub>	Turn-On Rise Time			5		ns
t <sub>D(off)</sub>	Turn-Off Delay Time			12		ns
t <sub>f</sub>	Turn-Off Fall Time			5		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =20A, di/dt=200A/μs		22		ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =20A, di/dt=200A/μs		20		nC

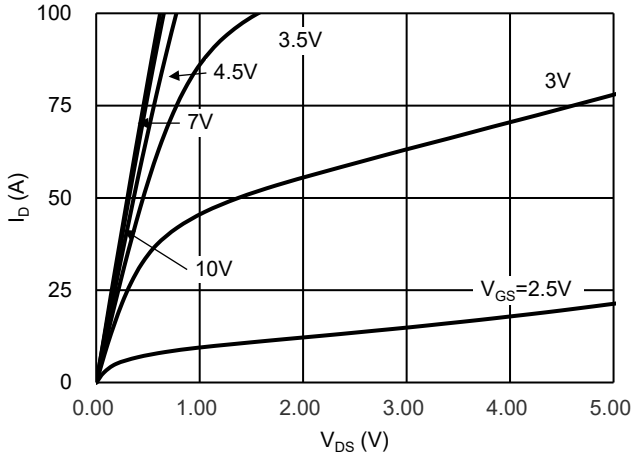
- 1) R<sub>θJA</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub> =25°C. The Power dissipation P<sub>DSM</sub> is based on R<sub>θJA</sub> ≤ 10s and the maximum allowed junction temperature of 150°C. The value in any given application depends on the user's specific board design.
- 2) The power dissipation P<sub>D</sub> is based on T<sub>J(MAX)</sub>=150°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
- 3) Single pulse width limited by junction temperature T<sub>J(MAX)</sub>=150°C.
- 4) R<sub>θJA</sub> is the sum of the thermal impedance from junction to case R<sub>θJC</sub> and case to ambient.
- 5) The maximum current rating is package limited.



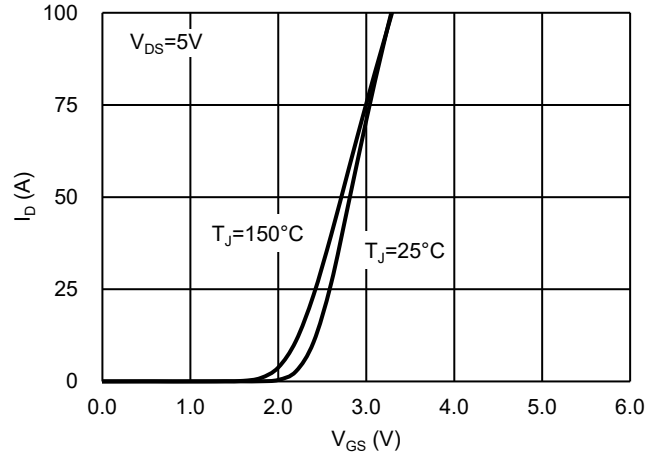
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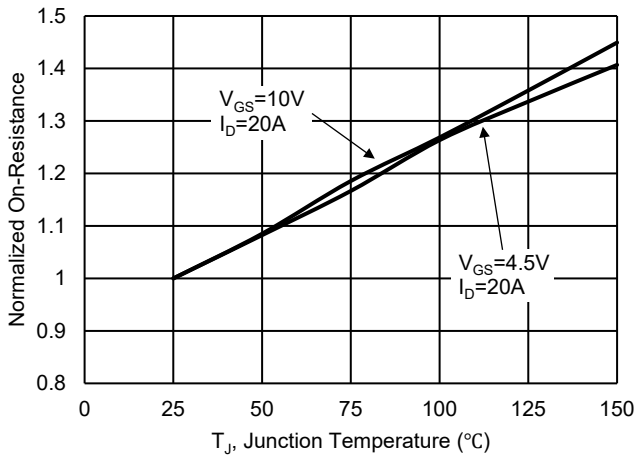
### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



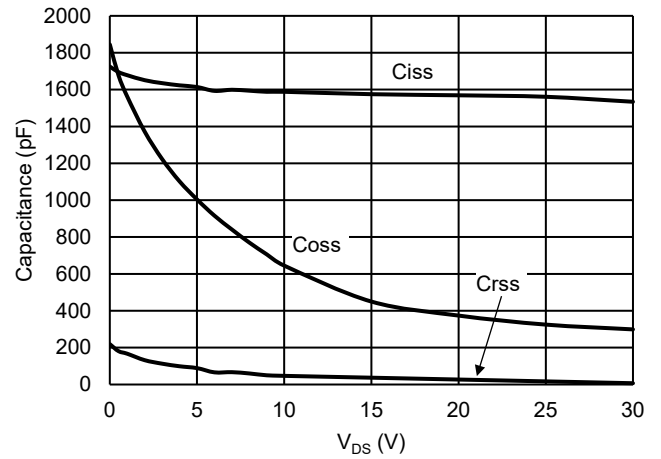
**Fig 1.** Typical Output Characteristics



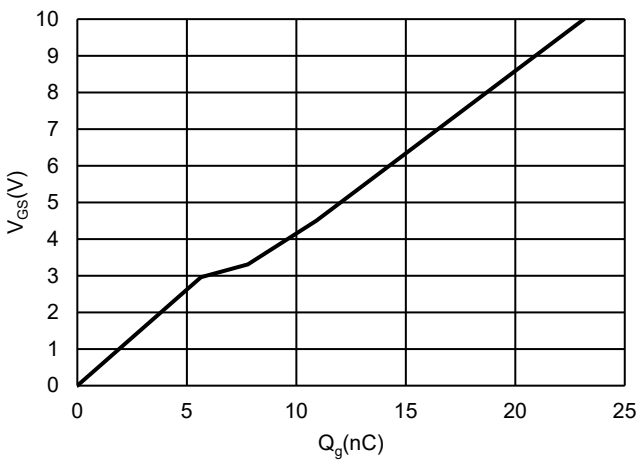
**Fig 2.** Typical Transfer Characteristics



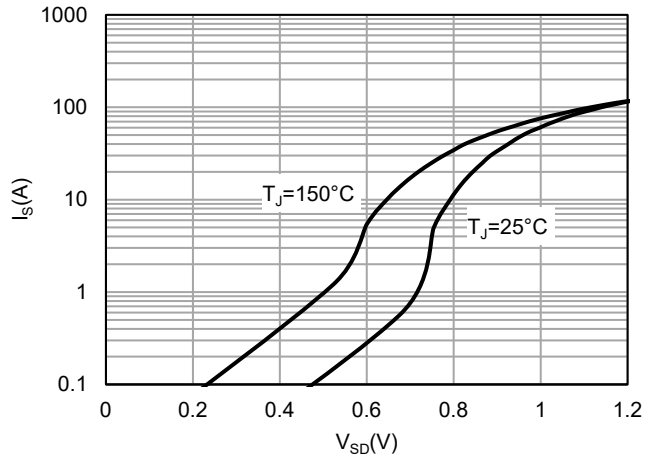
**Fig 3.** Normalized On-Resistance vs. Temperature



**Fig 4.** Typical Capacitance vs.  $V_{DS}$

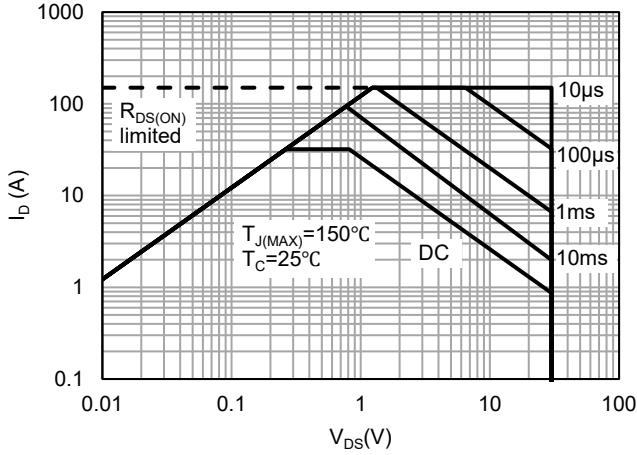


**Fig 5.** Typical Gate Charge vs.  $V_{GS}$

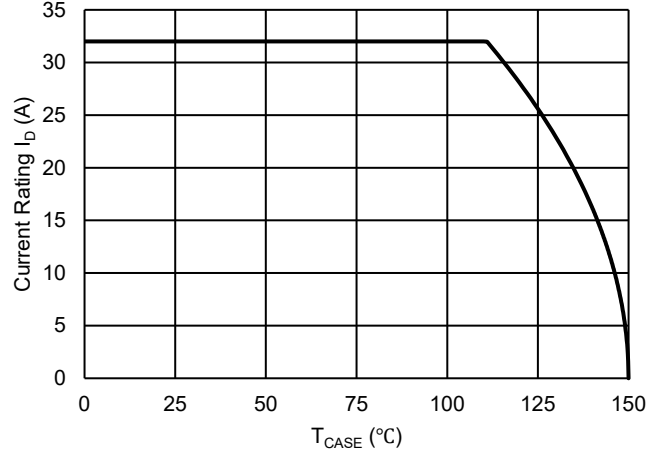


**Fig 6.** Typical Source-Drain Diode Forward Voltage

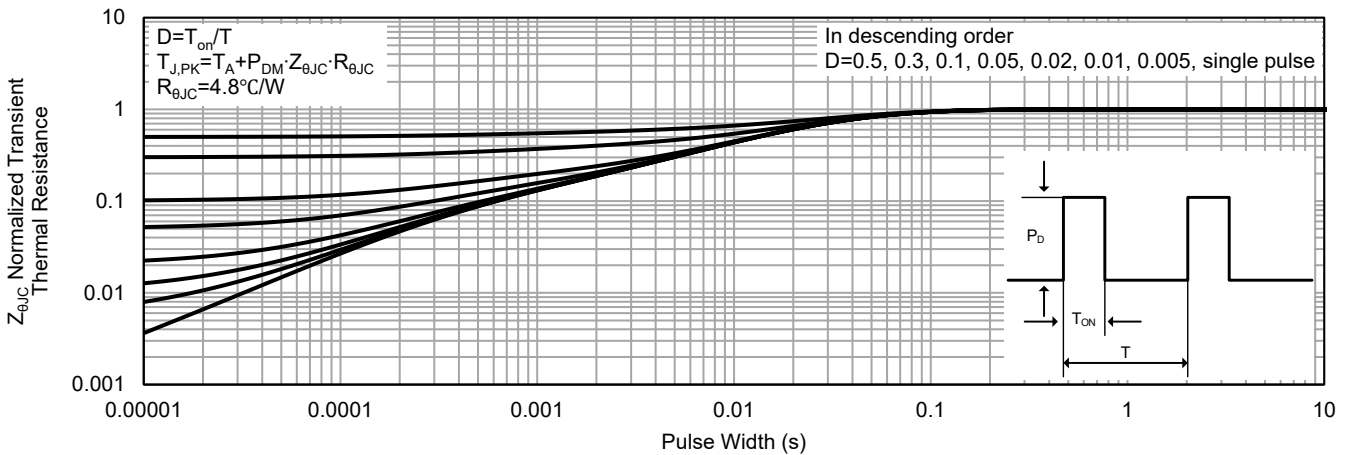
### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



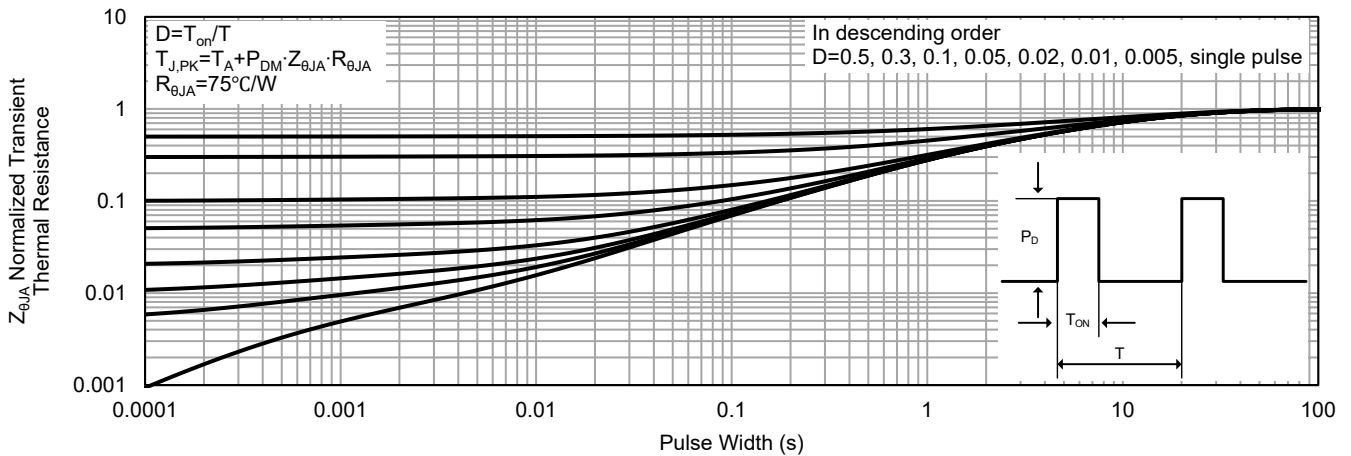
**Fig 7.** Maximum Safe Operating Area



**Fig 8.** Maximum Drain Current vs. Case Temperature

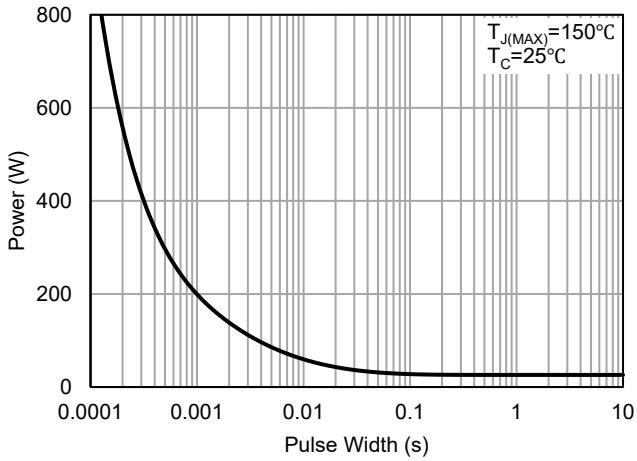


**Fig 9.** Normalized Maximum Transient Thermal Impedance, Junction-to-Case

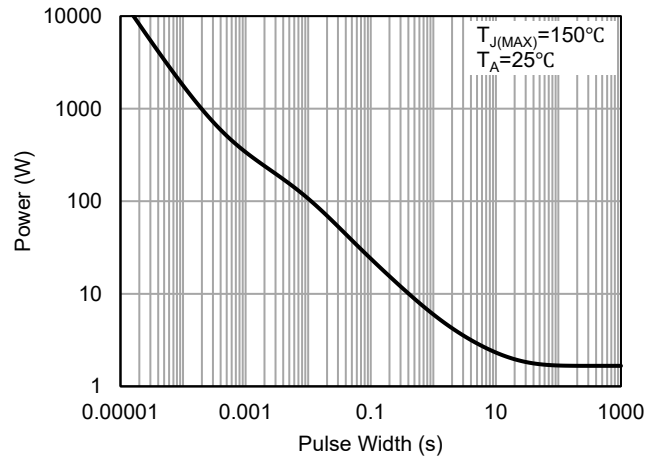


**Fig 10.** Normalized Maximum Transient Thermal Impedance, Junction-to-Ambient

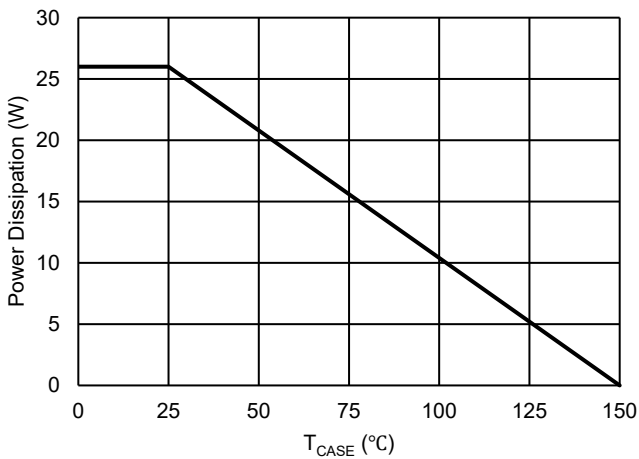
### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



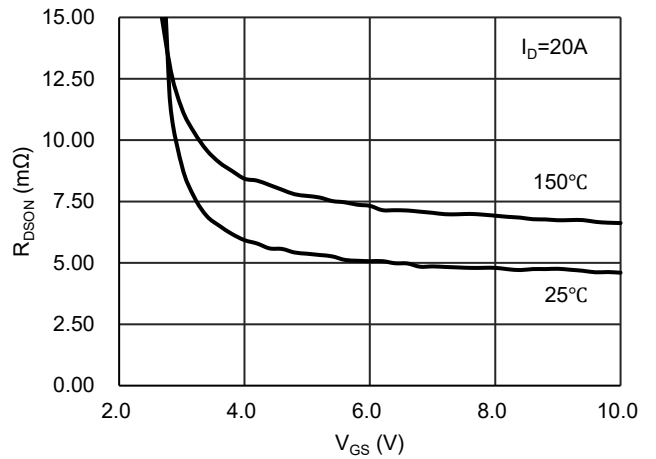
**Fig 11.** Single Pulse Power Rating Junction-to-Case



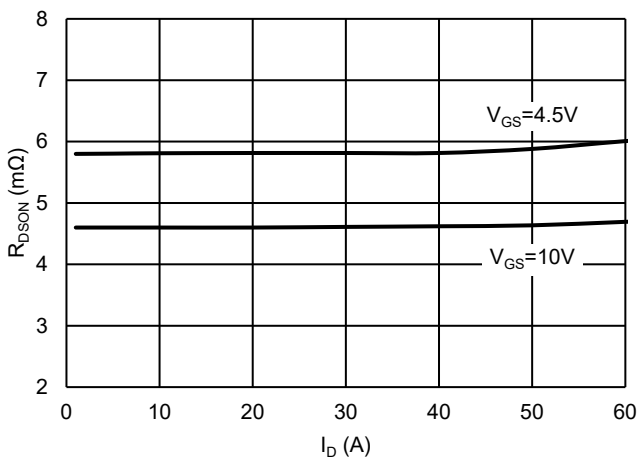
**Fig 12.** Single Pulse Power Rating Junction-to-Ambient



**Fig 13.** Maximum Power Rating vs. Temperature

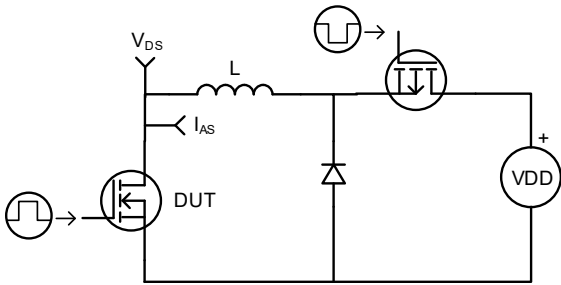


**Fig 14.** On-Resistance vs.  $V_{GS}$

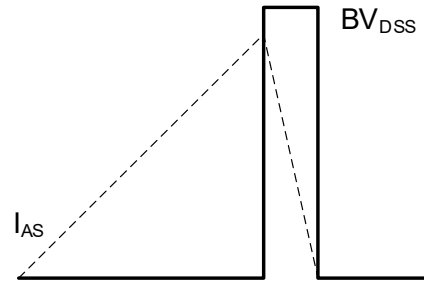


**Fig 15.** On-Resistance vs. Drain Current

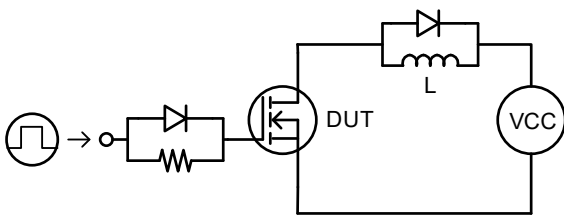
### TEST CIRCUIT



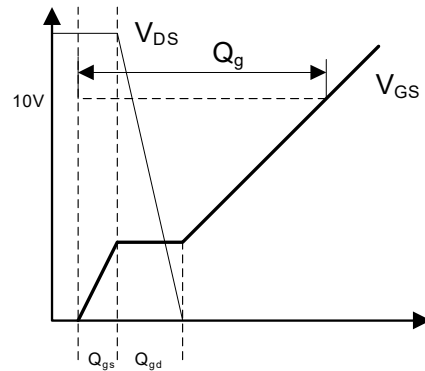
**Fig16.** Unclamped Inductive Test Circuit



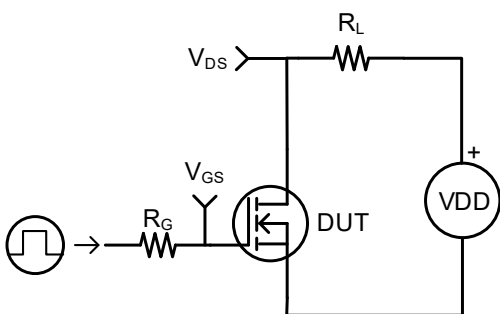
**Fig17.** Unclamped Inductive Waveform



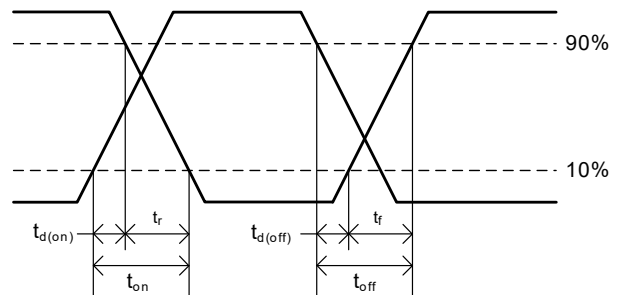
**Fig18.**  $Q_g$  Test Circuit



**Fig19.**  $Q_g$  Waveform



**Fig18.** Resistive Switching Test Circuit



**Fig19.** Switching Time Waveform

### TEST CIRCUIT

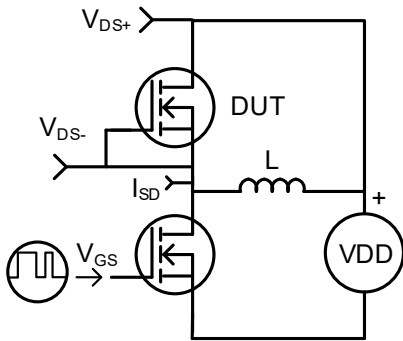


Fig20. Diode Recovery Test Circuit

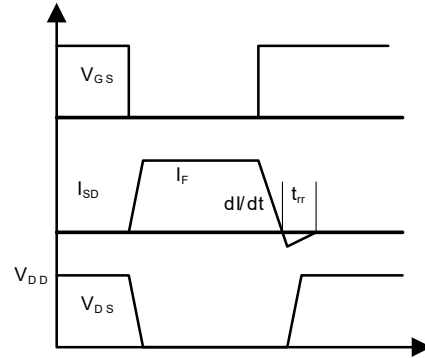
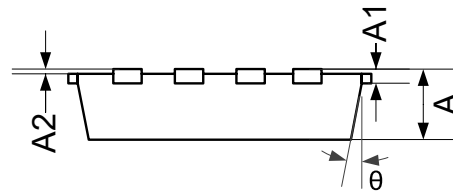
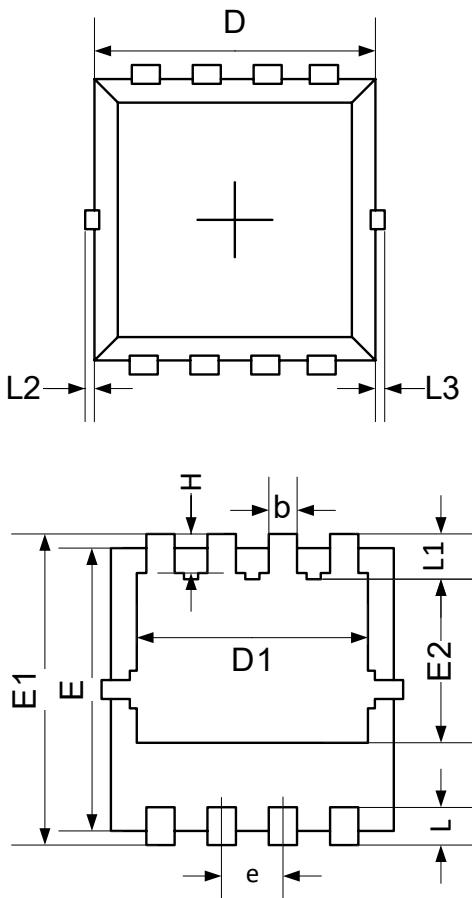


Fig21. Diode Recovery Test Waveform

### DFN3.3x3.3 OUTLINE



SYMBOL	DIM	MILLIMETERS	
		MIN [mm]	MAX [mm]
A		0.650	0.850
A1		0.152 REF	
A2		0~0.05	
D		2.900	3.100
D1		2.300	2.600
E		2.900	3.100
E1		3.150	3.450
E2		1.535	1.935
b		0.200	0.400
e		0.550	0.750
L		0.300	0.500
L1		0.180	0.480
L2		0~0.100	
L3		0~0.100	
H		0.315	0.515
$\theta$		9°	13°